

## ABSTRACT OF THE DISCLOSURE

5           A memory test controller comprises a test instruction register array for storing a plurality of test instructions, each register having instruction fields for storing instruction data specifying operations to be performed on the memory array, a repeat module for repeating a group of one or more of the test instructions with modified data, the repeat module including storage means for storing instruction field modification data; and each register of the test instruction register array including an instruction field for enabling or disabling the repeat module.